TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type ( $\pi$ -MOSIV)

# 2SK3880

### **Switching Regulator Applications**

• Low drain-source ON resistance: RDS (ON) =  $1.35 \Omega$  (typ.)

• High forward transfer admittance:  $|Y_{fs}| = 5.2 \mathrm{\ S}$  (typ.)

• Low leakage current:  $IDSS = 100 \mu A (max) (VDS = 640 V)$ 

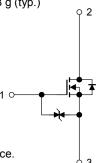
• Enhancement model:  $V_{th} = 2.0 \sim 4.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$ 

## **Maximum Ratings (Ta = 25°C)**

Characteristics			Symbol	Rating	Unit	
Drain-source voltage			$V_{DSS}$	800	V	
Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ )			V <sub>DGR</sub>	800	V	
Gate-source voltage			V <sub>GSS</sub>	±30	V	
Drain current	DC	(Note 1)	I <sub>D</sub>	6.5	Α	
	Pulse	(Note 1)	$I_{DP}$	19.5		
Drain power dissipation (Tc = 25°C)			$P_{D}$	80	W	
Single pulse avalanche energy (Note 2)			E <sub>AR</sub>	375	mJ	
Avalanche current			I <sub>AR</sub>	6.5	Α	
Repetitive avalanche energy (Note 3)			E <sub>AR</sub>	8	mJ	
Channel temperature			T <sub>ch</sub>	150	°C	
Storage temperature range			T <sub>stg</sub>	-55~150	°C	

# Unit: mm 15.8±0.5 2.0 2.0 1.6ATE 2.DRAIN 3.SOURCE JEDEC JEITA TOSHIBA 2-16F1B

### Weight: 5.8 g (typ.)



### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	1.56	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	41.6	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C during use of the device.

Note 2:  $V_{DD} = 90 \text{ V}$ ,  $T_{ch} = 25^{\circ}\text{C}$  (initial), L = 16.1 mH,  $R_G = 25 \Omega$ ,  $I_{AR} = 6.5 \text{ A}$ 

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Handle with care.

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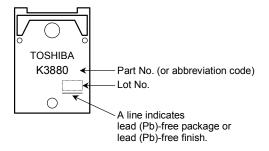
# **Electrical Characteristics (Ta = 25°C)**

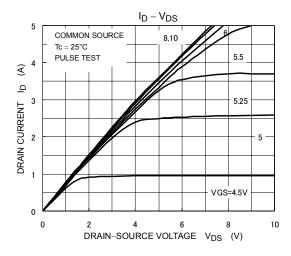
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	leakage current $I_{GSS}$ $V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$		$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μΑ
Drain-source breakdown voltage		V (BR) GSS	$I_G=\pm 10~\mu A,~V_{DS}=0~V$	±30	_	_	V
Drain cutoff current		I <sub>DSS</sub>	$V_{DS} = 640 \text{ V}, V_{GS} = 0 \text{ V}$	_	_	100	μΑ
Drain-source breakdown voltage V		V (BR) DSS	$I_D = 10$ mA, $V_{GS} = 0$ V	800			V
Gate threshold vo	ate threshold voltage $V_{th}$ $V_{DS} = 10 \text{ V}, I_D = 1 \text{ mA}$		$V_{DS} = 10 \text{ V}, I_D = 1 \text{ mA}$	2.0	-	4.0	V
Drain-source ON resistance		R <sub>DS</sub> (ON)	$V_{GS} = 10 \text{ V}, I_D = 3.5 \text{ A}$	_	1.35	1.7	Ω
Forward transfer admittance		Y <sub>fs</sub>	$V_{DS} = 20 \text{ V}, I_D = 3.5 \text{ A}$	2.5	5.2		S
Input capacitance	;	C <sub>iss</sub>		_	1500		
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	25		pF
Output capacitance		C <sub>oss</sub>		_	140	_	
Switching time	Rise time	t <sub>r</sub>	10 V I <sub>D</sub> = 3.5 A V <sub>OUT</sub>		35		- ns
	Turn-on time	t <sub>on</sub>	$V_{GS}$ $V_{GS}$ $V_{GS}$ $V_{DD} \simeq 400 \text{ V}$	_	80	—	
	Fall time	t <sub>f</sub>	Duty $\leq$ 1%, $t_W = 10 \mu s$	_	50		
	Turn-off time	t <sub>off</sub>		_	220	_	
Total gate charge (gate-source plus gate-drain)		Qg		_	35		
Gate-source charge		Q <sub>gs</sub>	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 6.5 \text{ A}$	_	22	_	nC
Gate-drain ("Miller") charge		Q <sub>gd</sub>		_	13	_	

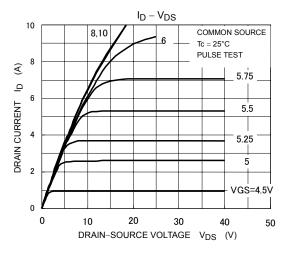
# Source-Drain Ratings and Characteristics (Ta = 25°C)

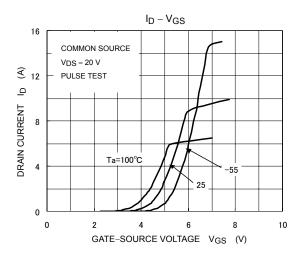
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	$I_{DR}$	_	_	_	6.5	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	-	_	19.5	Α
Forward voltage (diode)	V <sub>DSF</sub>	$I_{DR} = 6.5 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	-1.7	V
Reverse recovery time	t <sub>rr</sub>	$I_{DR} = 6.5 \text{ A}, V_{GS} = 0 \text{ V},$	_	1200	_	ns
Reverse recovery charge	Q <sub>rr</sub>	dI <sub>DR</sub> /dt = 100 A/μs	_	11.5	_	μС

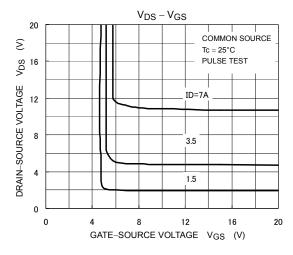
# Marking

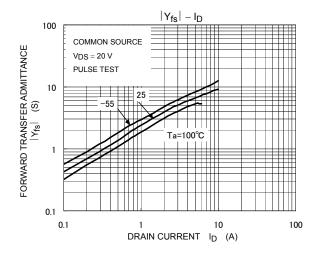


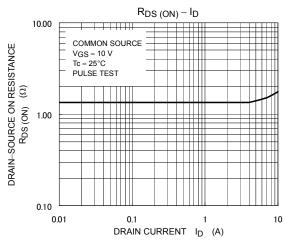


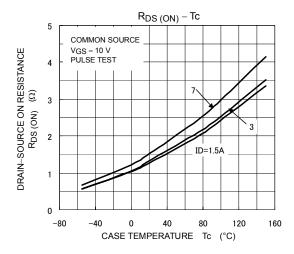


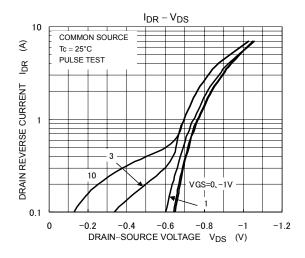


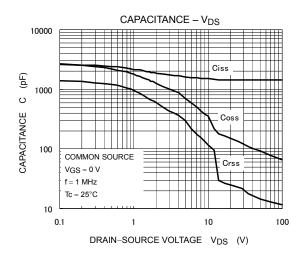


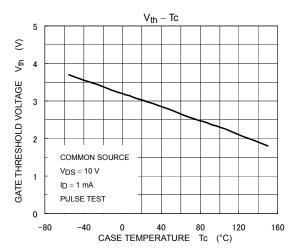


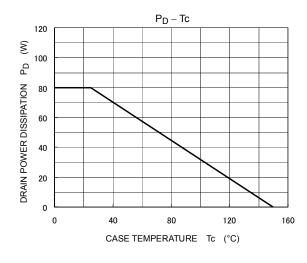


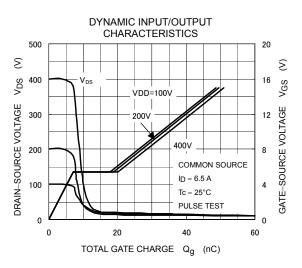




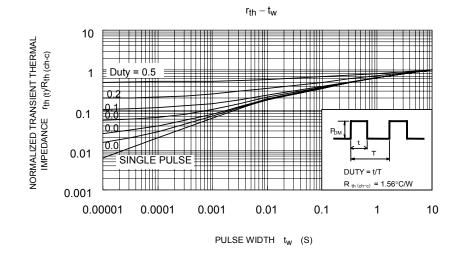


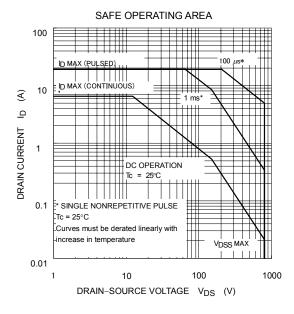


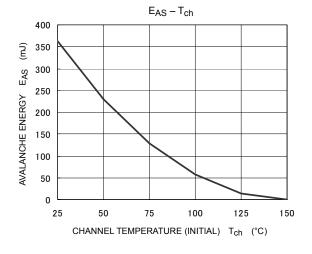


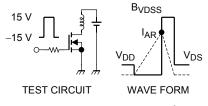


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$$R_G = 25 \Omega$$
  
 $V_{DD} = 90 \text{ V, L} = 16.1 \text{ mH}$   $E_{AS} = \frac{1}{2}$ 

$$E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left( \frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right)$$

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